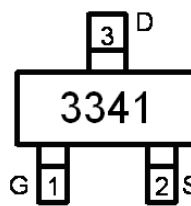
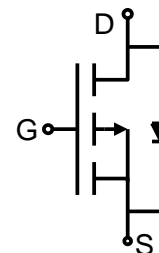


**Main Product Characteristics:**

$V_{DSS}$	-30V
$R_{DS(on)}$	39m $\Omega$ (typ.)
$I_D$	-4.2A ①


**SOT-23**

**Marking and Pin Assignments**

**Schematic Diagram**
**Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature
- Add "HF" for Halogen Free


**Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

**Absolute Max Rating:** @ $T_A=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Max.	Units
$I_D$ @ $TC = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V ①	-4.2	A
$I_D$ @ $TC = 70^\circ\text{C}$	Continuous Drain Current, $V_{GS}$ @ 10V ①	-3.5	
$I_{DM}$	Pulsed Drain Current ②	-30	
$P_D$ @ $TC = 25^\circ\text{C}$	Power Dissipation ③	1.4	W
$V_{DS}$	Drain-Source Voltage	-30	V
$V_{GS}$	Gate-to-Source Voltage	$\pm 12$	V
$T_J$ $T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ\text{C}$

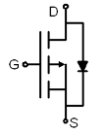
**Thermal Resistance**

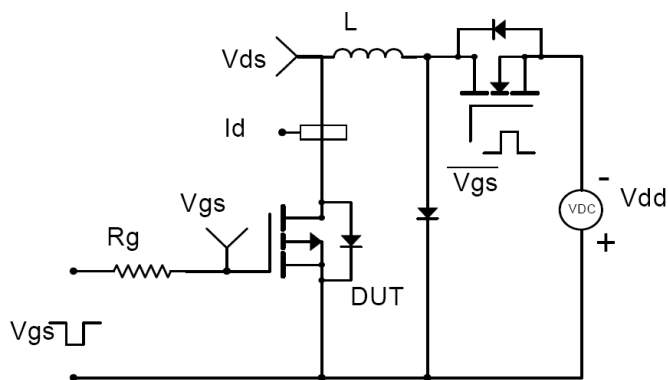
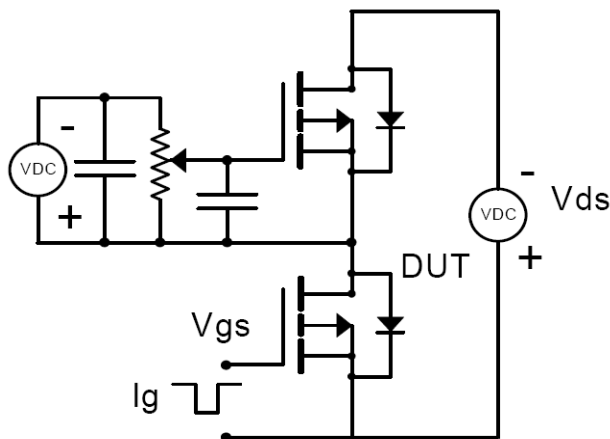
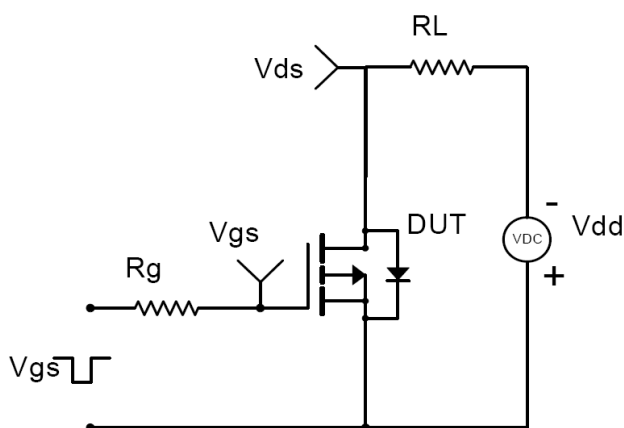
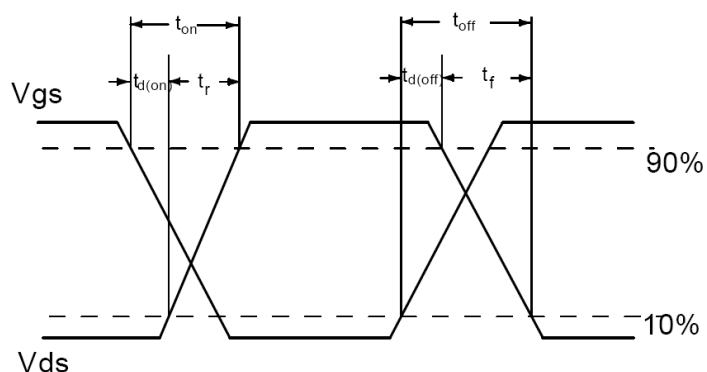
Symbol	Characterizes	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-ambient ( $t \leq 10\text{s}$ ) ④	—	90	$^\circ\text{C}/\text{W}$

**Electrical Characterizes @ $T_A=25^{\circ}\text{C}$  unless otherwise specified**

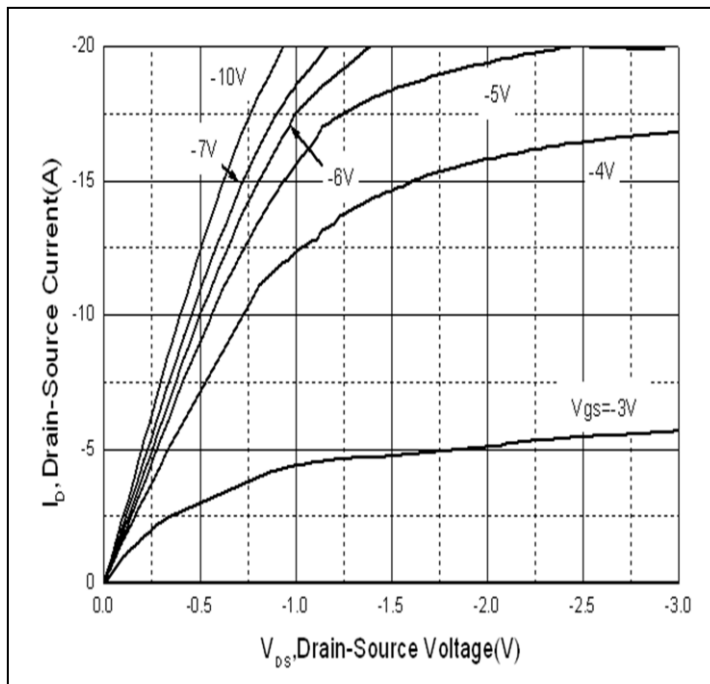
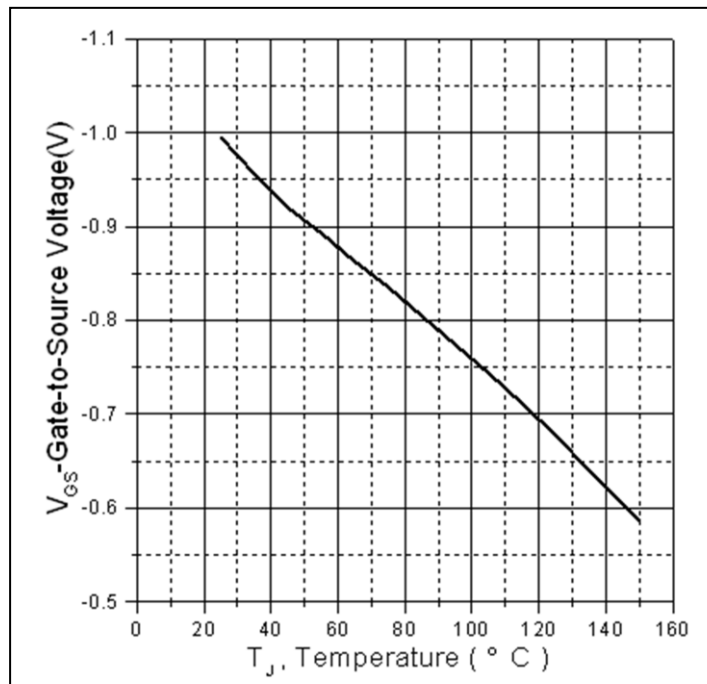
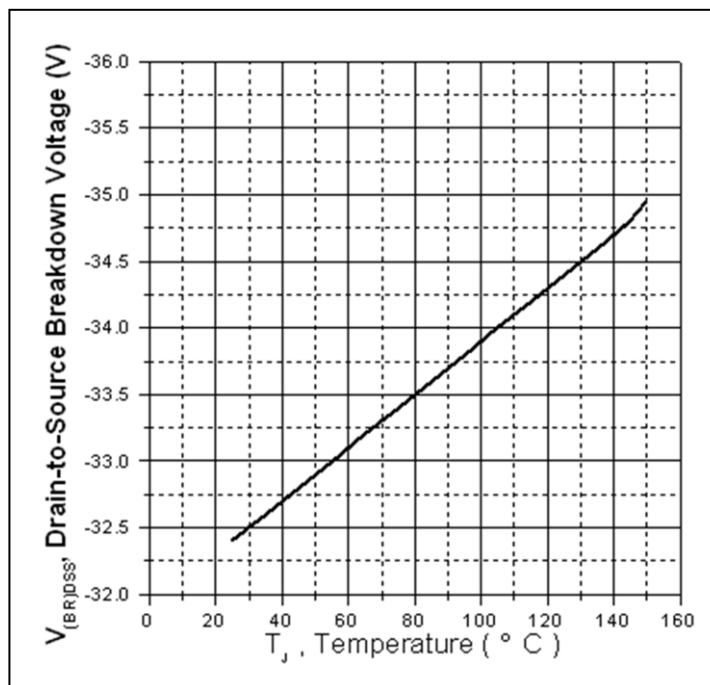
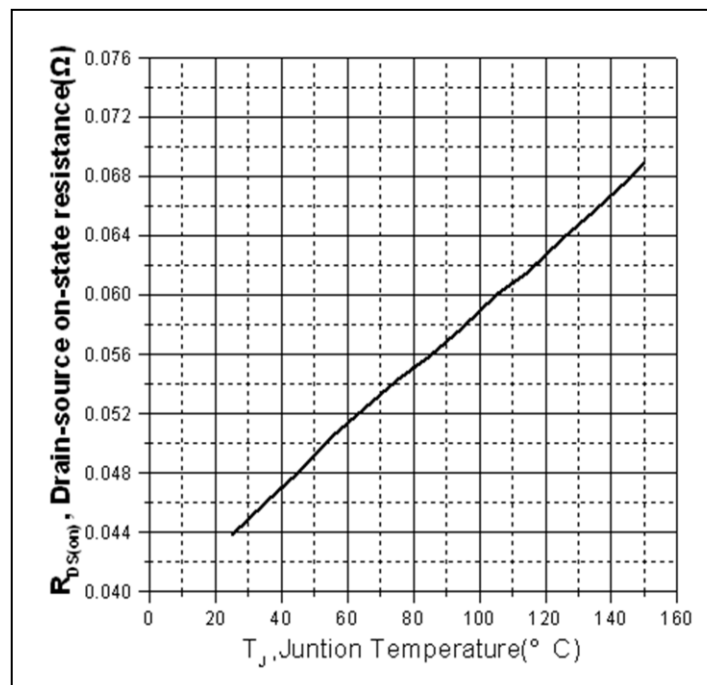
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	-30	—	—	V	$V_{GS} = 0V, I_D = -250\mu A$
$R_{DS(on)}$	Static Drain-to-Source on-resistance	—	39	50	m $\Omega$	$V_{GS}=-10V, I_D = -4.2A$
		—	48	65		$V_{GS}=-4.5V, I_D = -4A$
		—	68	120		$V_{GS}=-2.5V, I_D = -1A$
$V_{GS(th)}$	Gate threshold voltage	-0.7	—	-1.3	V	$V_{DS} = V_{GS}, I_D = -250\mu A$
		—	-0.68	—		$T_J = 125^{\circ}\text{C}$
$I_{DSS}$	Drain-to-Source leakage current	—	—	-1	$\mu A$	$V_{DS} = -24V, V_{GS} = 0V$
		—	—	-50		$T_J = 125^{\circ}\text{C}$
$I_{GSS}$	Gate-to-Source forward leakage	—	—	100	nA	$V_{GS} = 12V$
		—	—	-100		$V_{GS} = -12V$
$Q_g$	Total gate charge	—	18	—	nC	$I_D = -4A,$ $V_{DS}=-25V,$ $V_{GS} = -10V$
$Q_{gs}$	Gate-to-Source charge	—	2.1	—		
$Q_{gd}$	Gate-to-Drain("Miller") charge	—	2.7	—		
$t_{d(on)}$	Turn-on delay time	—	7.5	—	ns	$V_{GS}=-10V, V_{DS}=-15V,$ $R_{GEN}=3\Omega$
$t_r$	Rise time	—	15	—		
$t_{d(off)}$	Turn-Off delay time	—	26	—		
$t_f$	Fall time	—	3.7	—		
$C_{iss}$	Input capacitance	—	712	—	pF	$V_{GS} = 0V,$ $V_{DS} = -15V,$ $f = 1\text{MHz}$
$C_{oss}$	Output capacitance	—	82	—		
$C_{rss}$	Reverse transfer capacitance	—	67	—		

**Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode) ①	—	—	-4.2	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	-30	A	
$V_{SD}$	Diode Forward Voltage	—	-0.78	-1.0	V	

**Test Circuits and Waveforms**
**EAS Test Circuit:**

**Gate Charge Test Circuit:**

**Switching Time Test Circuit:**

**Switch Waveforms:**

**Notes:**

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

**Typical Electrical and Thermal Characteristics**

**Figure 1. Typical Output Characteristics**

**Figure 2. Gate to Source Cut-off Voltage**

**Figure 3. Drain-to-Source Breakdown Voltage vs. Junction Temperature**

**Figure 4. Normalized On-Resistance vs. Junction Temperature**

Typical Electrical and Thermal Characteristics

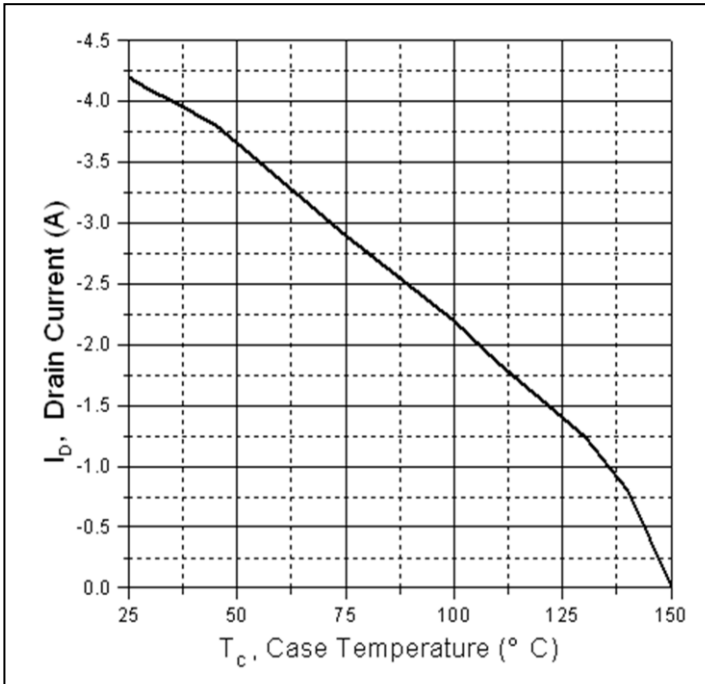


Figure 5. Maximum Drain Current vs. Case Temperature

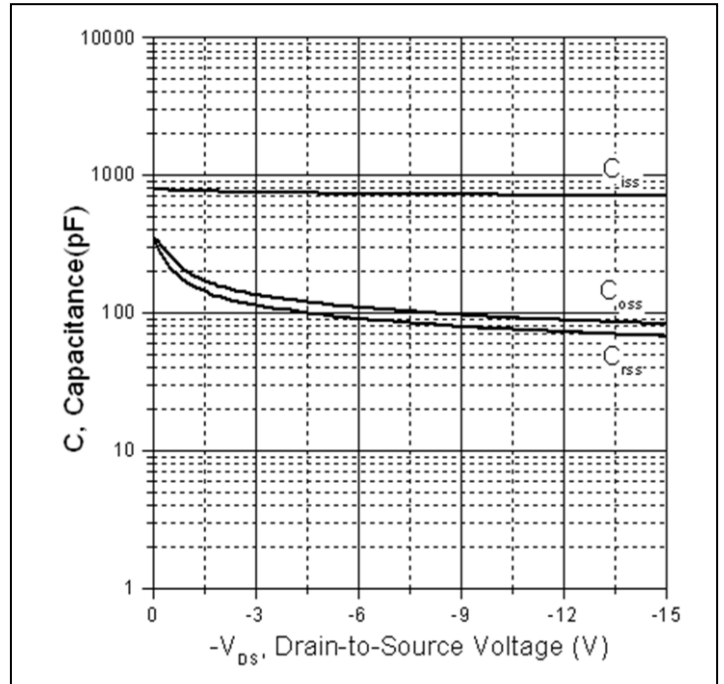


Figure 6. Typical Capacitance vs. Drain-to-Source Voltage

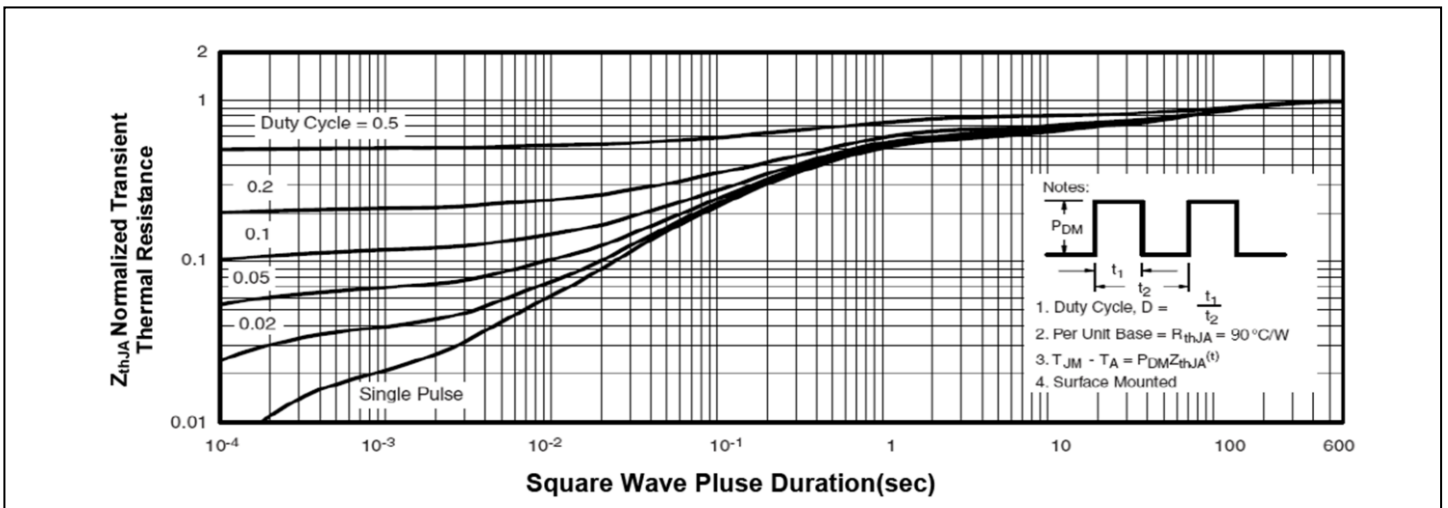
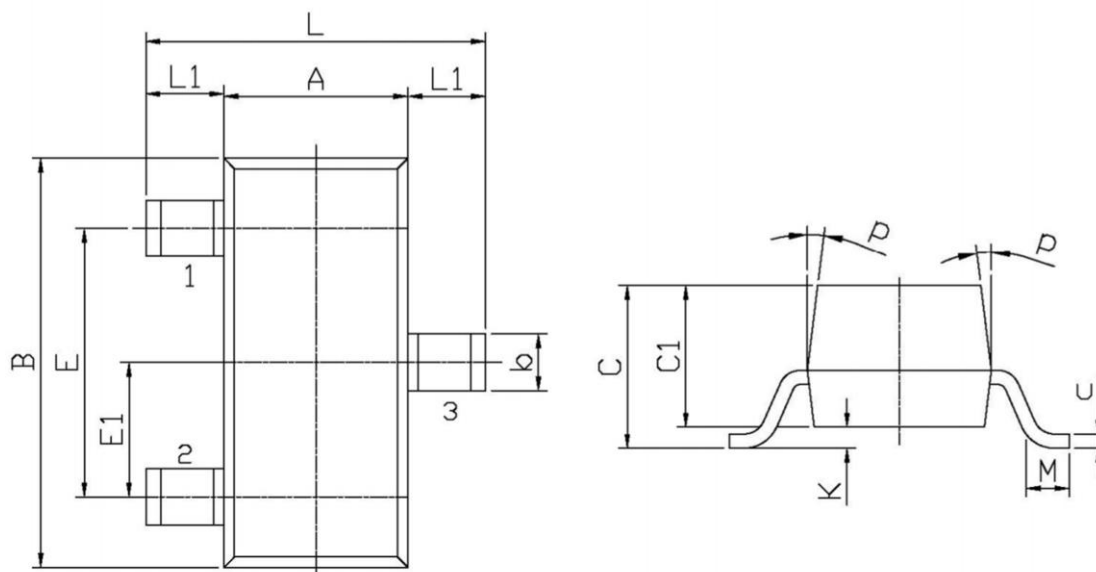


Figure7. Maximum Effective Transient Thermal Impedance Junction-to-Case

**Mechanical Data:**


Symbol	Dimensions In Millimeters		Symbol	Dimensions In Millimeters	
	Min	Max		Min	Max
L	2.2	2.7	C	1.30Max	
L1	0.45	0.65	C1	0.90	1.20
A	1.15	1.50	c	0.05	0.20
B	2.70	3.10	K	0	0.10
E	1.70	2.10	M	0.20MIN	
E1	0.85	1.05	P	7°	
b	0.35	0.55			

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